



ID de Contribution: 107

Type: Non spécifié

Technologies and Instrumentation for Line Intensity Mapping

vendredi 6 juin 2025 09:45 (40 minutes)

As the Line Intensity Mapping (LIM) field moves from upper limits to first detections to detailed characterization of the signal, increasingly sensitive, specialized instruments will need to be deployed. Technological advances—whether in spectrometer architecture, detector sensitivity, readout, signal processing, or instrument modeling—will enable the next generation of experiments. I will present an overview of the technologies used by LIM instruments over a wide range of wavelengths. Based on the sensitivity required for next-generation science goals, I will discuss promising avenues for improvement and how future LIM experiments might be configured.

Author: KARKARE, Kirit (Boston University)

Orateur: KARKARE, Kirit (Boston University)

Classification de Session: Keynote 8: Current and Future Technologies for Line Intensity Mapping